

Hardware trojan insertion in finalized layouts : from methodology to a silicon demonstration

Perez, Tiago Diadami; Pagliarini, Samuel Nascimento IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems 2023 / p. 2094-2107 <https://doi.org/10.1109/TCAD.2022.3223846> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

High-level test data generation for software based self-test in microprocessors

Oyeniran, Adeboye Stephen; Jasnetski, Artjom; Tšertov, Anton; Ubar, Raimund-Johannes 2017 6th Mediterranean Conference on Embedded Computing (MECO) : including ECYPS'2017 : proceedings : research monograph : Bar, Montenegro, June 11th-15th, 2017 2017 / p. 86-91 : ill <https://doi.org/10.1109/MECO.2017.7977167>

Implementation-independent functional test for transition delay faults in microprocessors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan 2020 23rd Euromicro Conference on Digital System Design (DSD), 26-28 August 2020, Kranj, Slovenia 2020 / p. 646-650 <https://doi.org/10.1109/DSD51259.2020.00105>

Logic IP for low-cost IC design in advanced CMOS nodes

Isgenc, Mehmet Meric; Martins, Mayler G.A.; Zackriya, V. Mohammed; **Pagliarini, Samuel Nascimento**; Pileggi, Larry IEEE Transactions on Very Large Scale Integration (VLSI) Systems 2020 / p. 585-595 <https://doi.org/10.1109/TVLSI.2019.2942825>

A new measure for calculating multiple fault coverage of microprocessor self-test

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Parallel pseudo-exhaustive testing of array multipliers with data-controlled segmentation

Oyeniran, Adeboye Stephen; Azad, Siavoosh Payandeh; Ubar, Raimund-Johannes 2018 IEEE International Symposium on Circuits and Systems (ISCAS) : 27-30 May 2018, Florence, Italy : proceedings 2018 / 5 p.: ill <https://doi.org/10.1109/ISCAS.2018.8350936> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)